

EAST - [10715690.wsp:1]

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DBs: IIS-PCPUB USPAT EPO: ☐ Fluke

Default operator: ☐ OR ☒ Highlight all hit terms initially

via and core and (C4 near assembly C-4 near connection C4) and signal near output and semiconductor and (printed near wiring near board printed near circuit near board) and package\$3

5RS form I5R form Image Text HTML

Drafts
Pending
Active
 L1: (0) microvia\$1 and core and (C4 near assembly C-4 near connection C4) and footprint near image)
 L2: (11) microvia\$1 and core and (C4 near assembly C-4 near connection C4)
 L3: (6681) via\$1 and core and (C4 near assembly C-4 near connection C4)
 L4: (63) via and core and (C4 near assembly C-4 near connection C4) and signal near output and se...
 L5: (0) microvia\$1 and core and (C4 near assembly C-4 near connection C4) and signal near output
 L6: (5) microvia\$1 and core and signal near output
 L7: (399) (microvia\$1) and signal near output and printed near wiring near board and semico...
 L8: (56) 7 and (C4 near assembly C4)
 L9: (0) (microvia\$1) and signal near output and printed near wiring near board and semiconductor...
 L10: (2) (microvia\$1) and signal near output and printed near wiring near board and core
 L11: (1) ("4016463").PN.
 L12: (1) ("5095407").PN.
 L13: (1) ("5834785").PN.
 L14: (1) ("6348400").PN.
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	U	I	Document ID	Issue Date	Pages	Title	Current OR	Current XRef
5	<input type="checkbox"/>	<input type="checkbox"/>	US 20040053290 A1	20040318	112	Devices and methods for biochip multiplexing	435/6	205/777.5; 435/287.2
6	<input type="checkbox"/>	<input type="checkbox"/>	US 20020167282 A1	20021114	175	High frequency inductive lamp and power oscillator	315/248	
7	<input type="checkbox"/>	<input type="checkbox"/>	US 20020132378 A1	20020919	18	Wafer level system for producing burn-in/screen, and reliability evaluations to be performed on all chips simultaneously without any wafer contact	438/14	324/765
8	<input type="checkbox"/>	<input type="checkbox"/>	US 20020165096 A1	20020808	16	SEMICONDUCTOR DEVICE WITH CONNECTION TERMINALS IN THE FORM OF A GRID ARRAY	257/786	257/E23.069; 257/E23.07; 257/E25.013
9	<input type="checkbox"/>	<input type="checkbox"/>	US 20020074953 A1	20020620	88	INDUCTIVE-RESISTIVE FLUORESCENT APPARATUS AND METHOD	315/248	315/291
10	<input type="checkbox"/>	<input type="checkbox"/>	US 20020020905 A1	20020221	24	Crosspoint switch with switch-matrix module	257/686	257/690; 257/692
11	<input type="checkbox"/>	<input type="checkbox"/>	US 6844747 B2	20050118	18	Wafer level system for producing burn-in/screen, and reliability evaluations to be performed on all chips simultaneously without any wafer contact	324/750	324/765
12	<input type="checkbox"/>	<input type="checkbox"/>	US 6808494 B1	20030819	12	Single point high resolution time resolved photoemission microscopy system and method	324/752	324/537
13	<input type="checkbox"/>	<input type="checkbox"/>	US 6487648 B1	20021126	20	SDRAM controller implemented in a PLD	711/167	326/39; 713/409; 713/503
14	<input type="checkbox"/>	<input type="checkbox"/>	US 6483327 B1	20021119	12	Quadrant avalanche photodiode time-resolved detection	324/752	324/158.1; 324/537
15	<input type="checkbox"/>	<input type="checkbox"/>	US 6459161 B1	20021001	16	Semiconductor device with connection terminals in the form of a grid array	257/786	257/737; 257/738; 257/E23.069